

| Ref # | Hits   | Search Query  | DBs  | Default Operator | Plurals | Time Stamp       |
|-------|--------|---|--|------------------|---------|------------------|
| L1    | 21     | (US-20050122352-\$ or US-20040263544-\$ or US-20030063174-\$ or US-20050140751-\$ or US-20020105566-\$ or US-20020003551-\$).did. or (US-5572241-\$ or US-5369420-\$ or US-6467862-\$ or US-6012793-\$ or US-5400066-\$ or US-6679582-\$ or US-6431678-\$ or US-6402277-\$ or US-5953031-\$ or US-5428378-\$ or US-6074036-\$ or US-6929356-\$). did. or (JP-06143612-\$ or JP-05270007-\$ or JP-04320853-\$). did. | US-PGPUB; USPAT; JPO                               | OR               | ON      | 2005/09/29 08:24 |
| L2    | 6      | 1 and polyimide   | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:39 |
| L5    | 13     | 1 and voltage   | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:49 |
| L9    | 685686 | (sequentially "in turn")  | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:55 |
| L10   | 102730 | (sequentially "in turn") and electrode  | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:55 |
| L11   | 20354  | (sequentially "in turn") and electrode and leak\$4  | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:55 |
| L12   | 635    | (sequentially "in turn") and electrode and leak\$4 and "347"/\$. ccls.  | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/09/29 09:55 |

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| L13 | 85  | (sequentially "in turn") with electrode and leak\$4 and "347"/\$.ccls.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/29 09:56 |
| S1  | 417 | "347"/\$.ccls. and leak\$4 and electrode with (channel conduit passage)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/26 16:40 |
| S2  | 13  | "347"/19.ccls. and leak\$4 and electrode with (channel conduit passage)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/26 16:40 |
| S3  | 417 | "347"/\$.ccls. and leak\$4 and electrode with (channel conduit passage)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 08:53 |
| S4  | 13  | "347"/19.ccls. and leak\$4 and electrode with (channel conduit passage)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 08:35 |
| S5  | 12  | "347"/7.ccls. and leak\$4 and electrode with (channel conduit passage)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 09:21 |
| S7  | 29  | "347"/6.ccls. and leak\$4  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 09:26 |
| S11 | 246 | "347"/\$.ccls. and (detect\$3 identify find\$4 discover\$3) with leak\$4 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 09:31 |

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| S12 | 139     | "347"/\$.ccls. and (detect\$3 identify find\$4 discover\$3) with leak\$4 and electrode                 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 10:44 |
| S15 | 664     | "347"/\$.ccls. and capillary with tube   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 10:27 |
| S16 | 220     | "347"/\$.ccls. and (capillary with tube) and leak\$4   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 10:28 |
| S18 | 70      | "347"/\$.ccls. and (capillary ink) with tube and (detect\$3 identify find\$4 discover\$3) with leak\$4 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 10:30 |
| S22 | 8316    | ink near\$5 leak\$4  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:30 |
| S23 | 58640   | detect\$4 with leak\$4   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:30 |
| S24 | 2133219 | voltage  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:31 |
| S25 | 1637013 | electrode  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:31 |

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| S27 | 191755 | electrode with (passage chamber<br>channel conduit) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:31 |
| S28 | 270529 | cartridge   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:32 |
| S29 | 39350  | cross near3 talk                                    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:32 |
| S30 | 65     | S22 and S23 and S24                                 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 13:40 |
| S31 | 14937  | (S22 S23).ti.                                       | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:34 |
| S32 | 1892   | S31 and S24   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:35 |
| S33 | 79     | S31 and S24 and S27                                 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 11:35 |
| S35 | 288893 | leak\$4.ab.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 13:43 |

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| S36 | 715 | "347"/\$.ccls. and S35   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:07 |
| S37 | 50  | S36 and S23  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 13:43 |
| S38 | 281 | "347"/6.ccls.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:08 |
| S39 | 299 | "347"/96.ccls.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:08 |
| S40 | 21  | "347"/96.ccls. and (leak\$4)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:15 |
| S42 | 80  | 137/15.11.ccls.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:33 |
| S43 | 257 | 347/19.ccls. and (conductor metal electrode) same (passage channel conduit chamber)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:48 |
| S45 | 5   | 347/19.ccls. and (conductor metal electrode) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near\$5 leak\$4 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 15:57 |
| S46 | 4   | ("5572241").URPN.  | USPAT   | OR | ON | 2005/09/27 15:52 |

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| S47 | 9      | 347/19.ccls. and (conductor metal electrode sensor) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near5 leak\$4 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:01 |
| S48 | 2      | 347/23.ccls. and (conductor metal electrode sensor) same (passage channel conduit chamber) and (detect\$3 identif\$3 find\$3) near5 leak\$4 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:01 |
| S50 | 452358 | (su chang chen lee chou).in.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:38 |
| S51 | 998    | (su chang chen lee chou).in. and leak\$4.ti.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:39 |
| S52 | 33     | (su chang chen lee chou).in. and leak\$4.ti. and electrode.clm.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:42 |
| S53 | 17     | (su chang chen lee chou).in. and leak\$4.ti. and (electrode and leak\$4).clm.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:44 |
| S54 | 856    | "347"/\$.ccls. and cross near3 talk   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/27 16:55 |

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| S55 | 19  | (US-20050122352-\$ or US-20040263544-\$ or US-20030063174-\$ or US-20050140751-\$ or US-20020105566-\$ or US-20020003551-\$).did. or (US-5572241-\$ or US-5369420-\$ or US-6467862-\$ or US-6012793-\$ or US-5400066-\$ or US-6679582-\$ or US-6431678-\$ or US-6402277-\$ or US-5953031-\$ or US-5428378-\$). did. or (JP-06143612-\$ or JP-05270007-\$ or JP-04320853-\$). did. | US-PGPUB;<br>USPAT;<br>JPO  | OR | ON | 2005/09/28 10:03 |
| S60 | 10  | (individual\$3 independent\$3) and S55  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 09:26 |
| S63 | 3   | (individual\$3 independent\$3) same voltage and S55   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 09:28 |
| S64 | 3   | (individual\$3 independent\$3) same electrode and S55   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 09:29 |
| S71 | 4   | S55 and display   | US-PGPUB;<br>USPAT;<br>JPO  | OR | ON | 2005/09/28 10:45 |
| S73 | 3   | "6679582"   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 10:52 |
| S74 | 16  | control\$3 and S55  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 11:15 |
| S75 | 615 | "347"/\$.ccls. and printhead same glass   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 11:15 |

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| S76 | 42  | "347"/20.ccls. and printhead same glass  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 11:20 |
| S77 | 6   | S55 and glass  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 11:49 |
| S79 | 0   | nozzle with polyimide and 347/20.ccls.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 11:50 |
| S80 | 3   | nozzle with polyimide and "347"/\$.ccls.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:18 |
| S81 | 714 | 347/87.ccls.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:18 |
| S82 | 373 | 347/87.ccls. and leak\$4   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:18 |
| S83 | 306 | 347/87.ccls. and leak\$4 and (electrode conductor pad contact)                                     | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:19 |
| S84 | 130 | 347/87.ccls. and leak\$4 and (electrode conductor pad contact) with (channel path conduit chamber) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:20 |



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| S85 | 16 | 347/87.ccls. and leak\$4.ab. and (electrode conductor pad contact) with (channel path conduit chamber) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 12:25 |
| S86 | 24 | 347/86.ccls. and leak\$4.ab. and (electrode conductor pad contact) with (channel path conduit chamber) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 14:06 |
| S87 | 34 | 347/86.ccls. and leak\$4 adj between   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 14:57 |
| S88 | 3  | 347/86.ccls. and leak\$4 adj between near (channel conduit chamber passage)                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 14:59 |
| S89 | 0  | 347/87.ccls. and leak\$4 adj between near (channel conduit chamber passage)                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 14:59 |
| S90 | 11 | "347"/\$.ccls. and leak\$4 adj between near (channel conduit chamber passage)                          | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 15:10 |
| S91 | 5  | S90 and (conductor electrode pad contact) with (channel passage conduit chamber)                       | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 15:08 |
| S92 | 3  | "101"/\$.ccls. and leak\$4 adj between near (channel conduit chamber passage)                          | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 15:24 |

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| S93 | 172 | "347"/\$.ccls. and leak\$4 near5<br>between near5 (channel conduit<br>chamber passage)               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 15:29 |
| S95 | 47  | "347"/\$.ccls. and leak\$4 near5<br>between near5 (channel conduit<br>chamber passage) and detect\$3 | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/09/28 15:30 |